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Sommario/riassunto	This issue of Direction focuses on the rapid proliferation of electron microscopy (EM) for scientific as well as technological research. The content written by leading experts is intended to provide the capabilities of EM facilities, set at Indian Institute of Technology (IIT) Kanpur to solve various problems and caters to the needs of both internal and external users. The book provides a detailed and comprehensive viewpoint of the basic features and advanced capabilities of EM facilities to the scientific community. A large number of electron microscopes have been installed and utilized by researchers

across various engineering and science departments; hence, this volume provides both breadth as well as depth of various EM facilities available at the institute.